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preparing the corporate accounting documents, declares in accordance with paragraph 2, Article 154-bis of Legislative Decree No. 58/1998 ("Consolidated Finance Act"), that the accounting information included in this presentation corresponds to the underlying accounting records, and ii) in accordance with paragraph 5-ter, Article 154-bis of the Consolidated Finance Act.

This document makes use of some alternative performance indicators. The management of the Company considers these indicators key parameters to monitor the Group's economic and financial performance. As the represented indicators are not identified as accounting measurements according to IFRS standards, the Group calculation criteria may not be uniform with those adopted by other groups and, therefore, may not be comparable.

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Agenda





- 01 | Our Vision & Strategy Stefano Felici CEO
- 02 | Market Perspective Marco Prea CCO
- 03 | **Technology & Testing**Joe Parks CTO
- 04 | **Financial Outlook**Stefano Beretta CFO

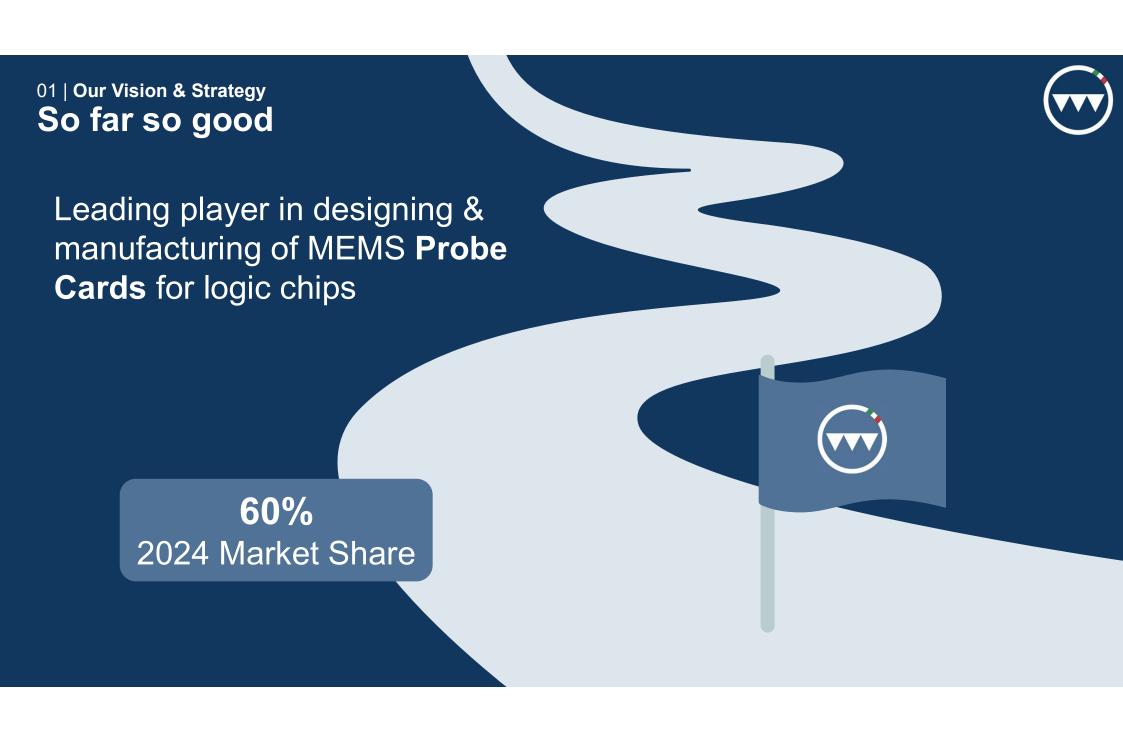
Agenda





01 | Our Vision & Strategy Stefano Felici - CEO





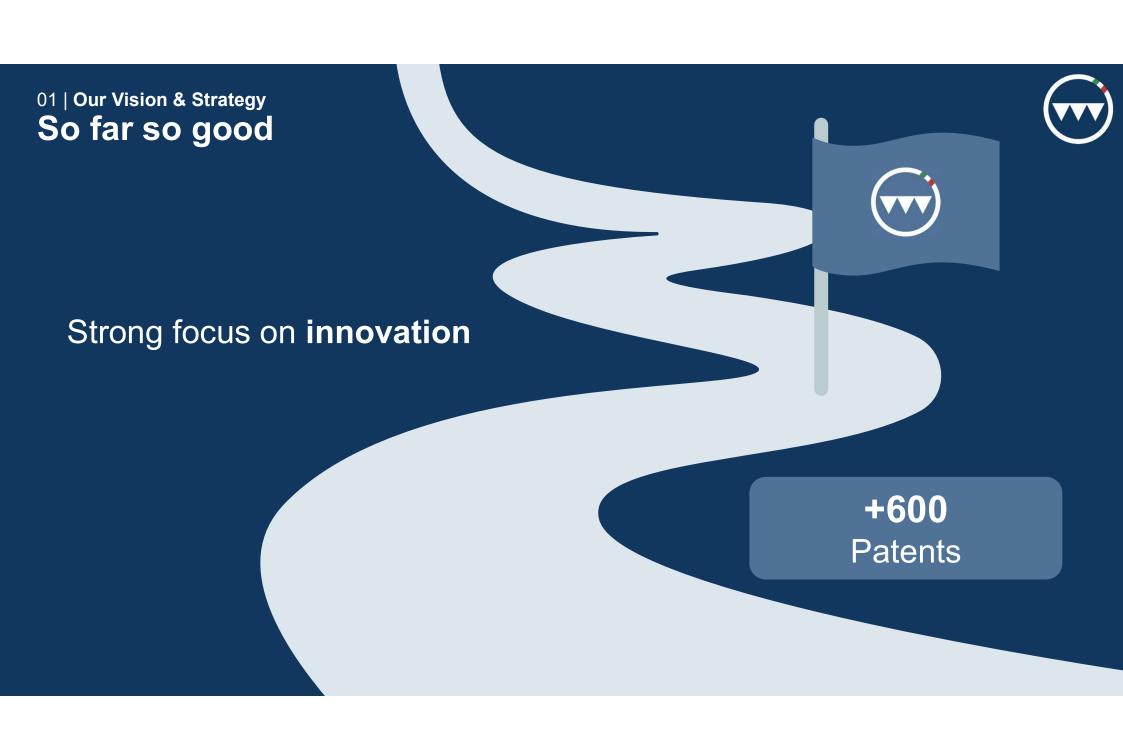
O1 | Our Vision & Strategy
So far so good

Customer satisfaction and reputation as cornerstone values



TSMC's Excellent Performance Award 2024

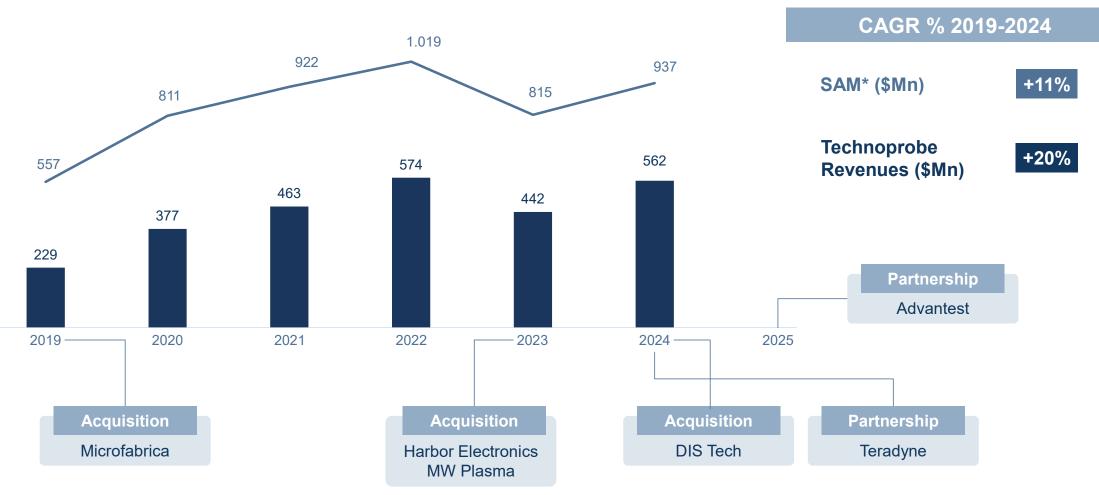




01 | Our Vision & Strategy So far so good Extensive global presence and widespread local footprint

Technoprobe evolution





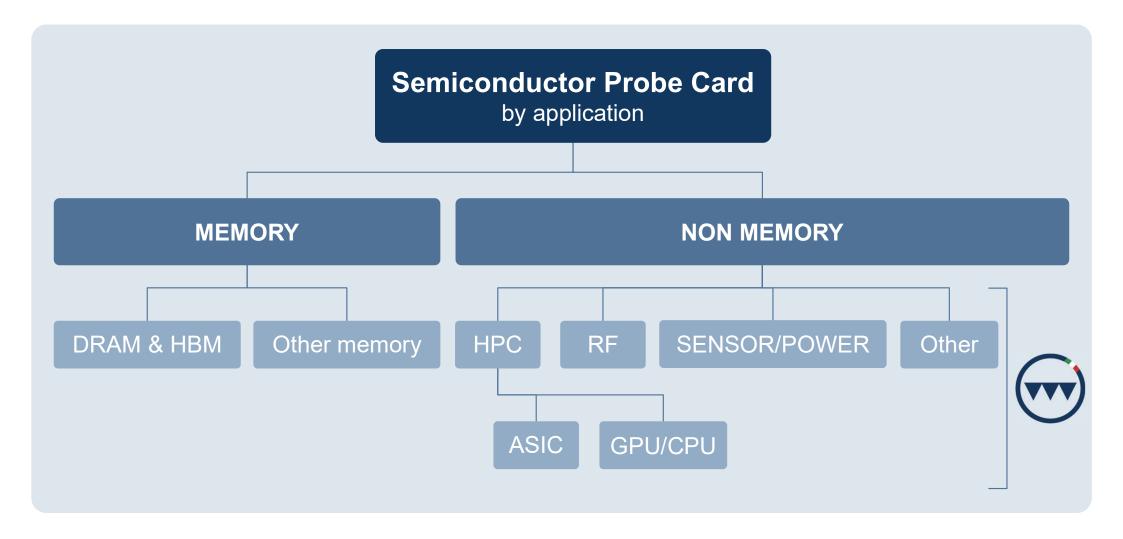
SAM*: MEMS Logic Probe Cards – Do not include Final Testing Market. Consistently, 2024 Revenues do not include Final Test for USD28m. Source: Yole – Semiconductor Test Consumables market monitor Q3 2024 (Sept.2024) – rounded figures. Revenues USD @ average annual exchange rate (CAGR €: +21.6%).

Our positioning in the testing space



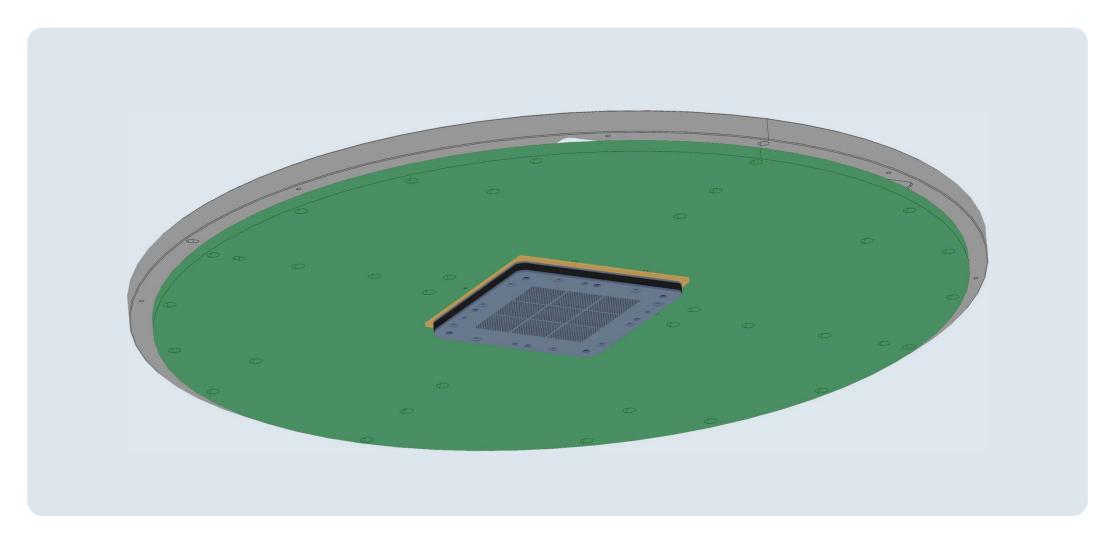
FRONT END		BACK END		
Wafer fabrication & pre-assembly preparation	Wafer Testing Level	Assembly	Packaging	Final Testing Level
	Wafer Level			Socket
	Singulated Die			System Level Testing
	Advanced Packaging			
			Device Interface Board	
	Probe Card			

Our positioning in the semiconductor Probe Card market



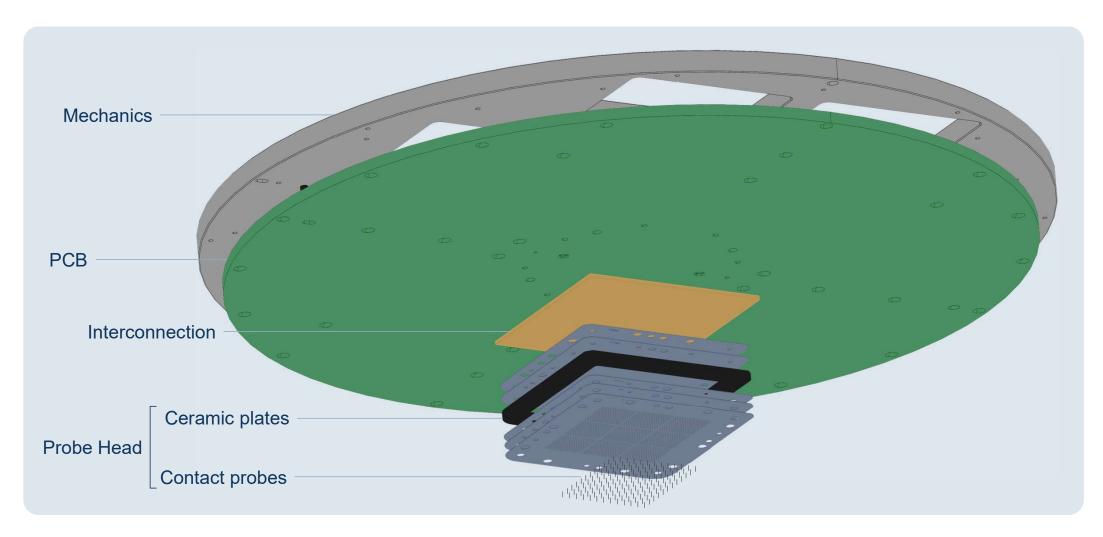
01 | Our Vision & Strategy The Probe Card



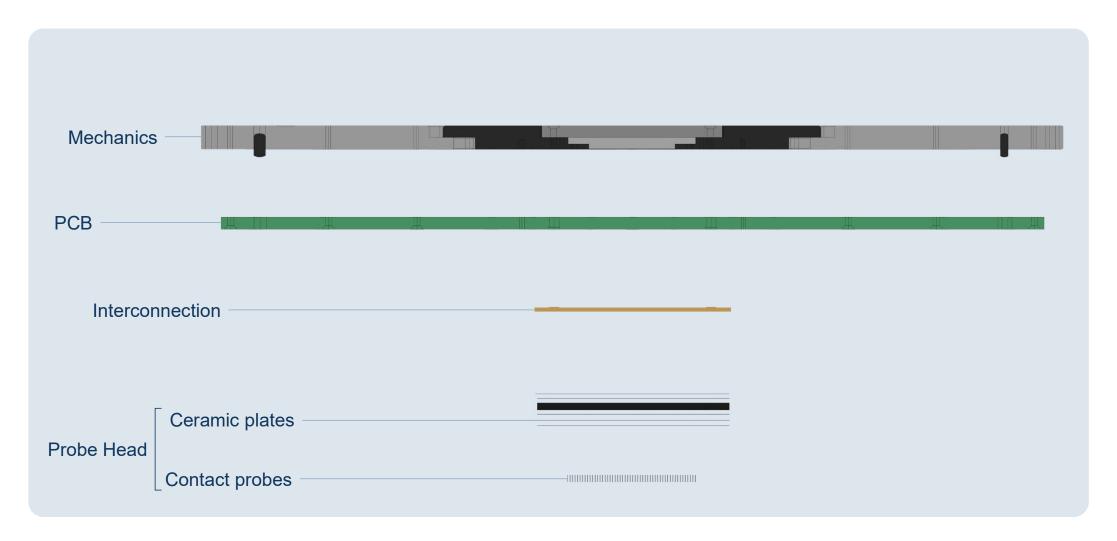


The Probe Card





The Probe Card



Our business model



	Design	Manufacturing	Assembly
Wafer Testing Level			
Mechanics			
PCB	— 💮	Manufacturing partners & other suppliers	
Interconnection			
Probe head Ceramic plates Contact probes			
Final Testing Level			
Device Interface Boards	<u> </u>	Manufacturing partners & other suppliers	

Built an open eco-system partnerships



TERADYNE

Accelerate growth of complete Probe Card and Final Test Interfaces by acquisition of DIS

Joint Development Projects to deliver superior customer value in SOC and Memory



ADVANTEST

Priority suppliers of PCB

Joint Development Projects to share knowledge

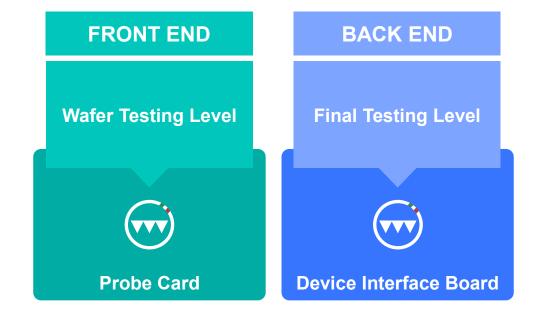
Challenges & strategic setting



1	Evolution of chip technology (more than Moore) Scaling slow down as enabler for chiplets, 3D architectures and new materials	 → Continuous investments in R&D → M&A as accelerator of technological development
2	Increase in complexity Design and manufacturing are becoming essential capabilities to reliably deliver complex solutions	 → Strategic partnerships → Vertical integration of the most value- added components of the probe card
3	Client satisfaction Reliability of the product & on-time delivery	→ Support on site→ Commercial agreements

01 | Our Vision & Strategy What's next?





01 | Our Vision & Strategy What's next?



Consolidate the leading positioning in all test segments

FRONT END

Drive advancements in Logic Semiconductor Testing

Proliferate high-speed, high-voltage, radio frequency and silicon photonics

Enter the High Bandwidth Memory (HBM) segment

BACK END

Strengthen positioning in Final Testing

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- 04 | **Mid-term Plan** Stefano Beretta - CFO

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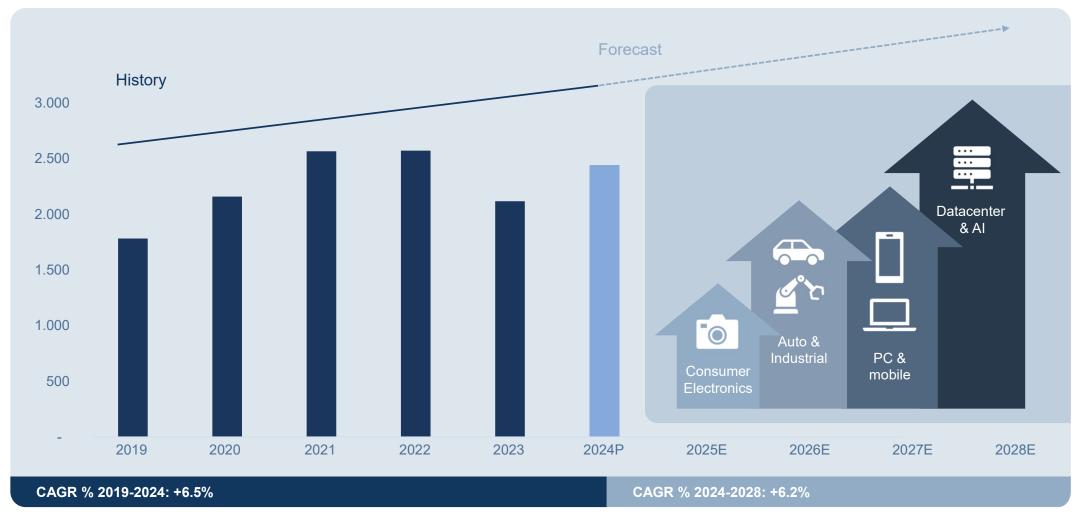


02 | Market Perspective Marco Prea - CCO



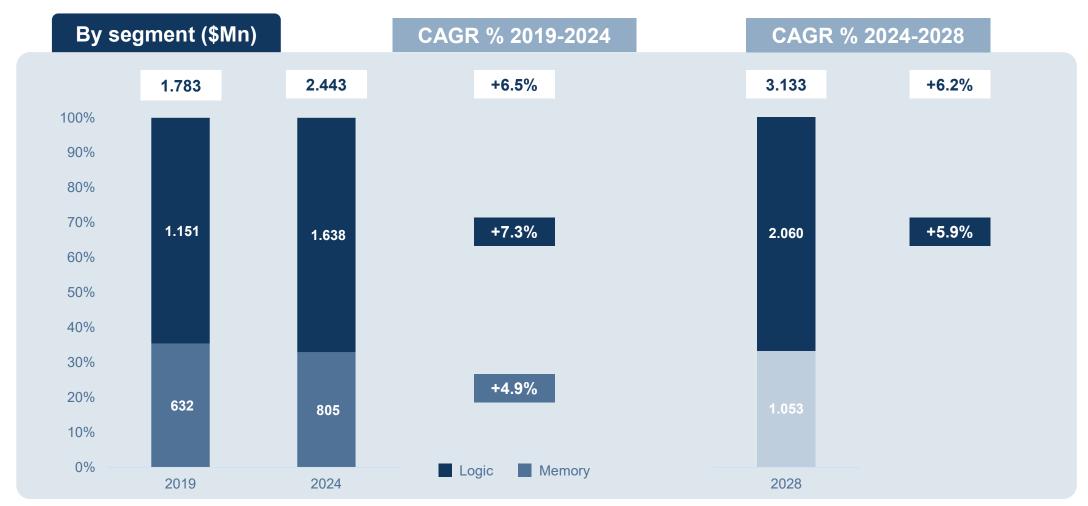
The Probe Card market (\$Mn)





The Probe Card market





Source: Yole - Semiconductor Test Consumables market monitor Q3 2024 (Sept.2024) - rounded figures. Memory: DRAM+NVM & Other memory. Logic: MEMS, Power, RF, CMOS Image Sensors, Photonics, Other non-memory, WAT.

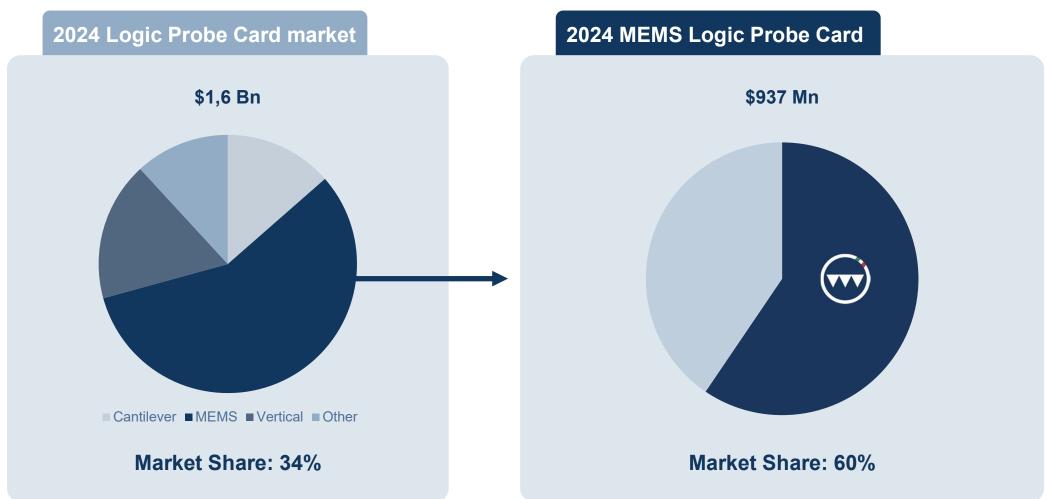
Logic Probe Card by technology





Our reference markets





Final Testing market – Advanced PCBs





Our reference markets





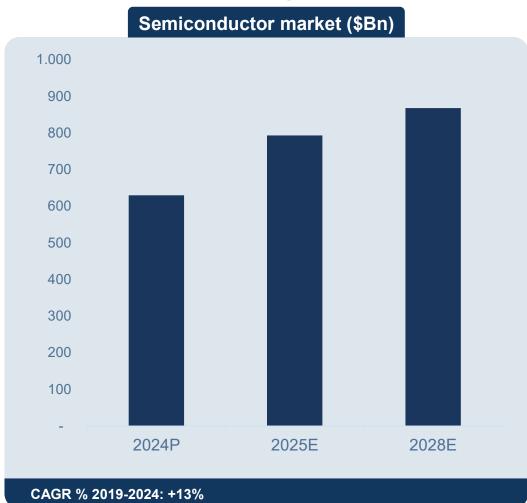


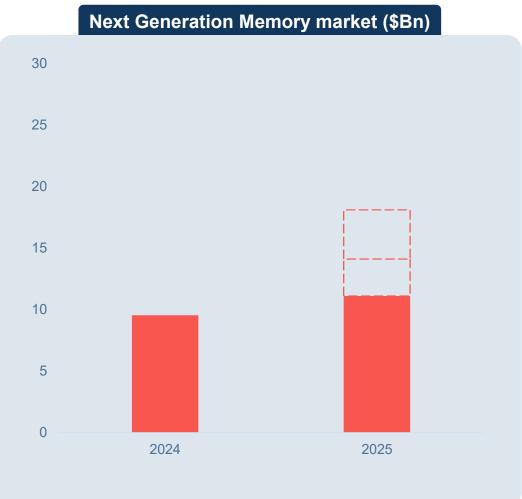
2024 Final Test DIB market



Focus on Memory market







Source: Yole and Precedence Research Estimates.

Key messages



MEMS Logic PC

Ever-growing market for leading edge technology

Key positioning on technological advances

Final Test

Immediate exposure to an expanded SAM

Technological breakthroughs from FusionLink

HBM

New challenge & opportunity

MEMS technology as a potential game changer

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Capital Market Day 2025

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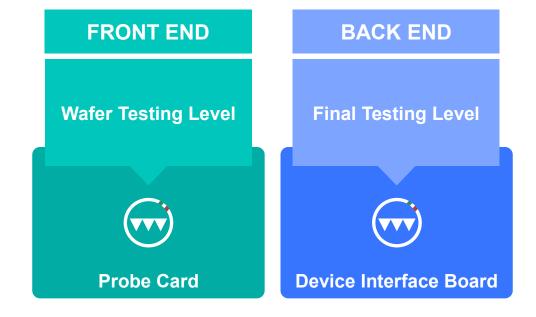
03 | Technology & Testing

Joe Parks - CTO



Growth drivers & trajectories





03 | Technology & Testing

Growth drivers & trajectories



FRONT END

Drive advancements in Logic Semiconductor Testing

Proliferate high-speed, high-voltage, radio frequency and silicon photonics

Enter the High Bandwidth Memory (HBM) segment

BACK END

Strengthen positioning in Final Testing

03 | Technology & Testing Growth drivers & trajectories



FRONT END

Drive advancements in Logic Semiconductor Testing

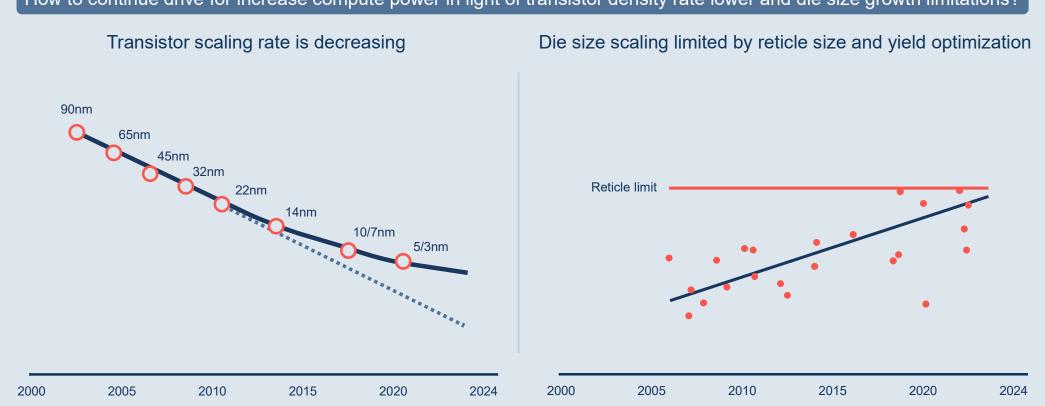
03 | Technology & Testing

Semiconductor technology trend



Industry motivation behind advanced packaging

How to continue drive for increase compute power in light of transistor density rate lower and die size growth limitations?



03 | Technology & Testing

Semiconductor technology trend

Solution: die disaggregation and advanced packaging



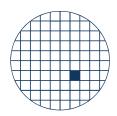
- Improved wafer-level yield with smaller chiplet
- Optimizing performance with mixed functionality capabilities
 - Memory
 - Co-packaged optics
- Allows for mixed technology node application and IP reuse

Source: Intel

Role of test in disaggregated world



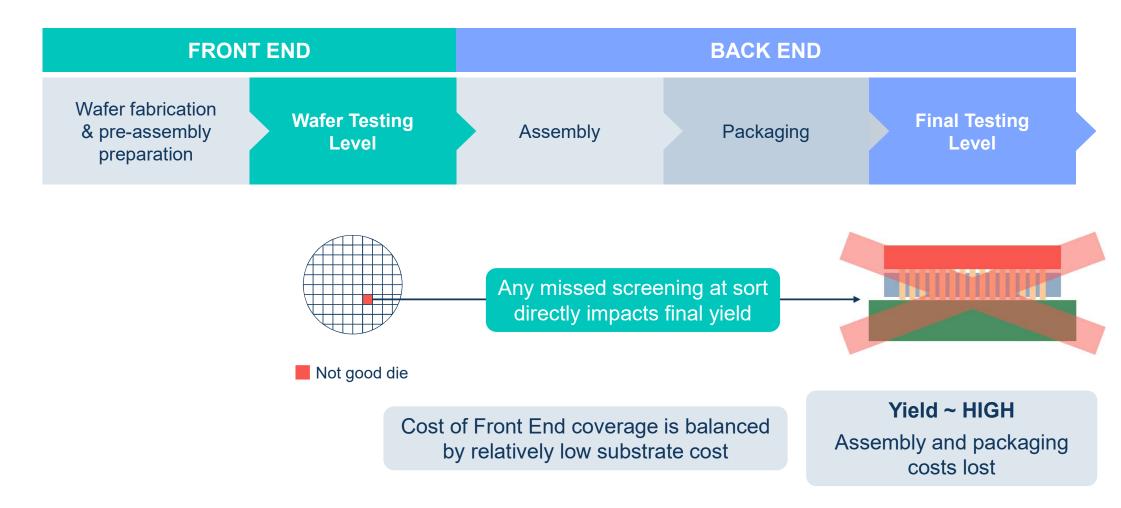
FRONT END		BACK END			
Wafer fabrication & pre-assembly preparation	Wafer Testing Level	Assembly	Packaging	Final Testing Level	



Easy example: **single die** into a package

Role of test in disaggregated world

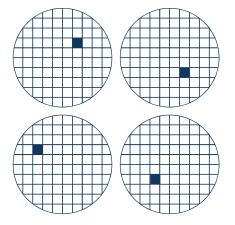




Role of test in disaggregated world



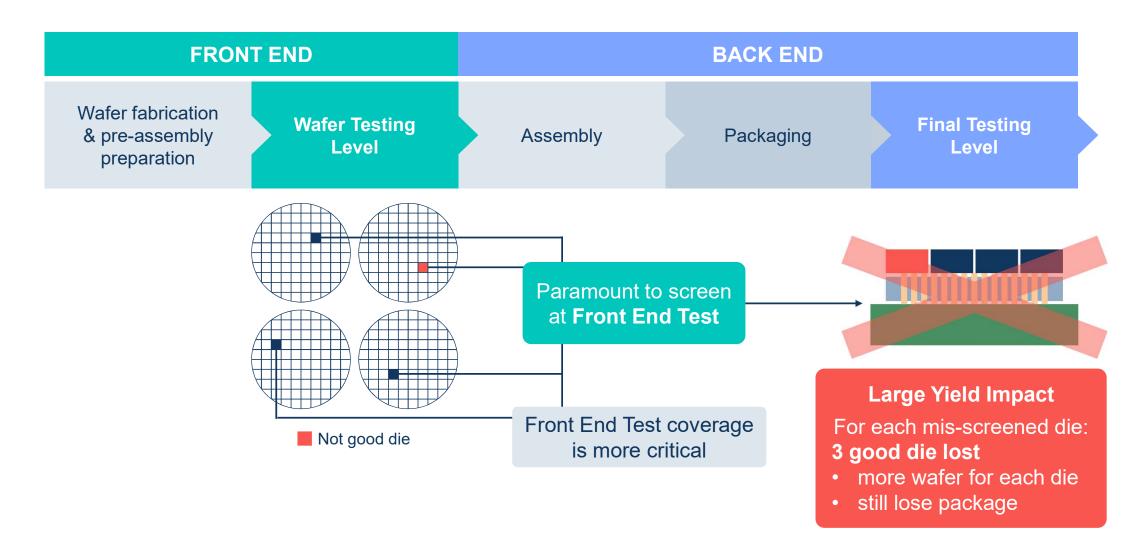




What about **four die**?

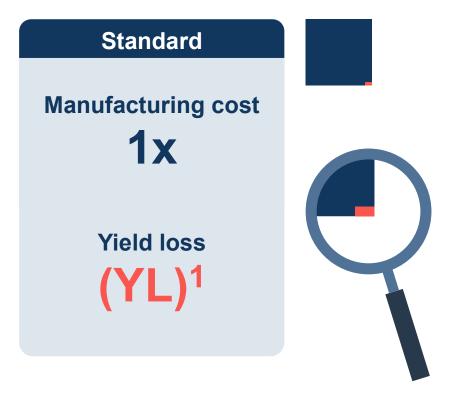
Role of test in disaggregated world





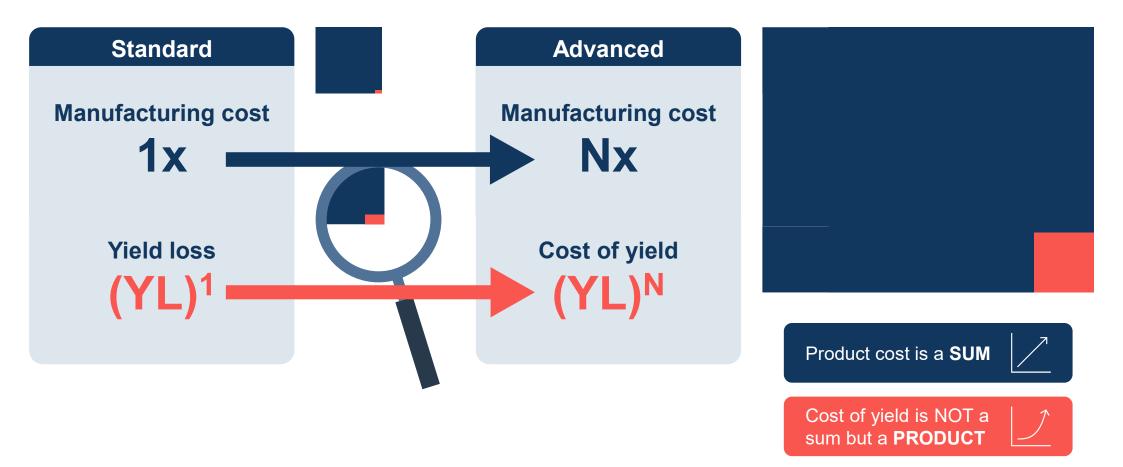
Advanced packaging vs standard





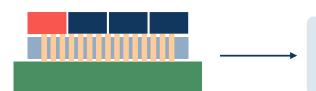
Advanced packaging vs standard





Role of test in disaggregated world





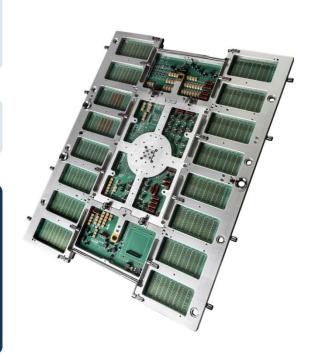
Front End Test coverage is more critical

True **Known Good Die** required!

SOLUTION

more test at probe

=
more Probe Cards



Technoprobe as advanced packaging enabler



Fine pitch and ultra-large pin count

Necessary to effectively probe HPC and HBM's and all leading-edge product

High-speed

Short, ultra short and RF-specific needles technology to manage high speed interconnect IO, including SiPh

High power and thermal

Delivering high power to DUT in effective and reliable way

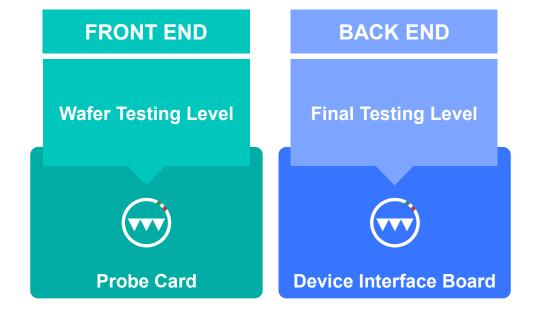
Ability to remove heat dissipated by the probe card (directly or because of power transferred from DUT to PC)

High-density interconnect

Ultra-high complexity PCB and MLO/MLC for resource fan-out on ATE/SLT

Growth drivers & trajectories





Growth drivers & trajectories



FRONT END

Drive advancements in Logic Semiconductor Testing

Proliferate high-speed, high-voltage, radio frequency and silicon photonics

Enter the High Bandwidth Memory (HBM) segment

BACK END

Strengthen positioning in Final Testing

Growth drivers & trajectories



FRONT END

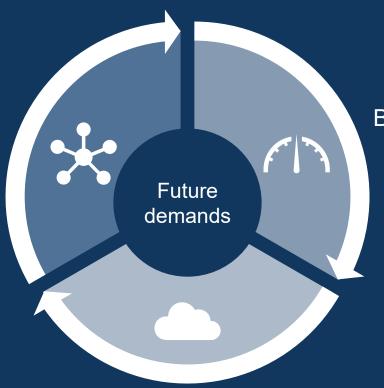
Proliferate high-speed, high-voltage, radio frequency and silicon photonics

A hungry world of wideband applications



Future demands on the network will be driven by a combination of factors:

Exponential increase in number & type of connected things



Bandwidth-hungry applications

Increasing reliance on the cloud

A hungry world of wideband applications



Future demands on the network will be driven by a combination of factors:

Exponential increase in number & type of connected things



Analog radio frequency

Satellite communications and sensing, automotive radar, mobile communication,...



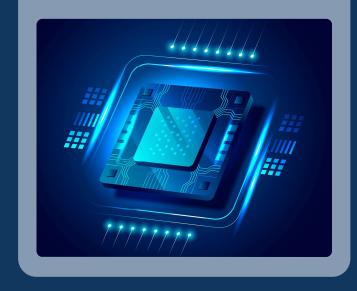
A hungry world of wideband applications



Future demands on the network will be driven by a combination of factors:

Silicon photonics

Chiplet to chiplet interconnect / photonics-driven computing





Bandwidth-hungry applications

A hungry world of wideband applications



Future demands on the network will be driven by a combination of factors:

Silicon photonics

Technoprobe technologies integrated in the same product enable...

Fine pitch probing

→ alignment with advanced packaging roadmap

Radio frequency probes

→ high-speed performances in same probe card solutions

Technoprobe IP

→ usage of standard wafer prober

Integration of other IP from specific segment suppliers

→ flexibility and compliancy with customer preferred test method

A hungry world of wideband applications



Future demands on the network will be driven by a combination of factors:

Chiplet probing

High density and high-speed IO inside chiplet demand for high-performance probe needles

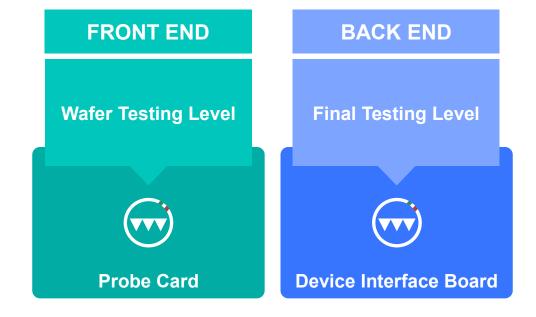
Future demands



Increasing reliance on the cloud

Growth drivers & trajectories





Growth drivers & trajectories



FRONT END

Drive advancements in Logic Semiconductor Testing

Proliferate high-speed, high-voltage, radio frequency and silicon photonics

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BACK END

Strengthen positioning in Final Testing

Growth drivers & trajectories

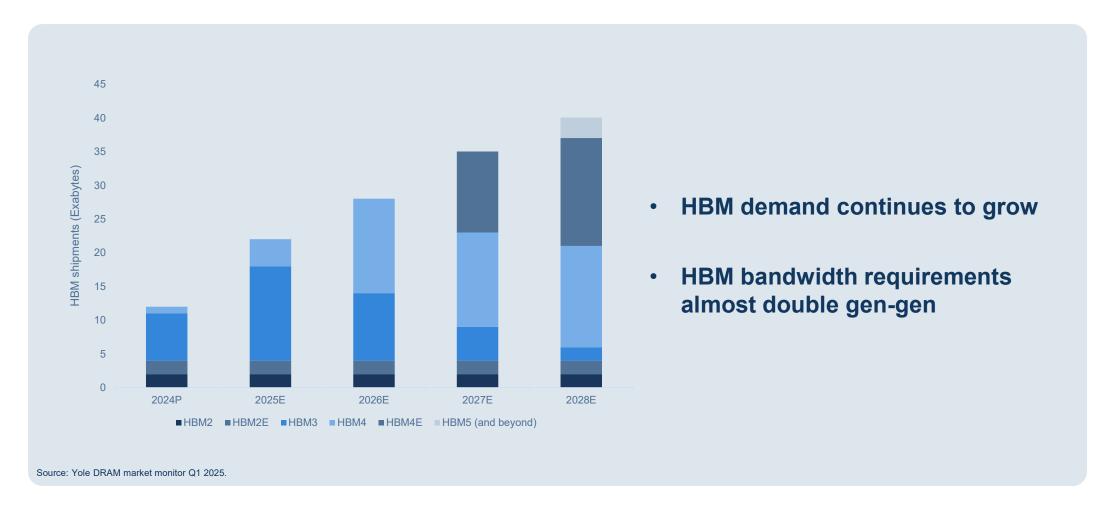


FRONT END

Enter the High Bandwidth Memory (HBM) segment

DRAM & HBM: complexity as driver to new products





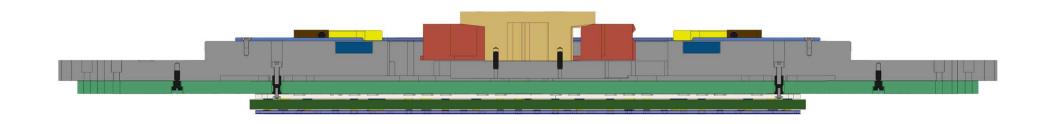
DRAM & HBM testing



DRAM and HBM are typically tested with **microcantilever** probing technologies.

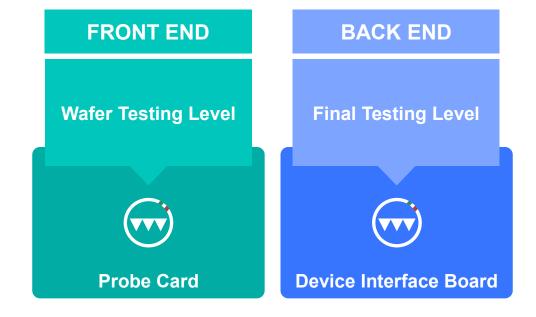
Most **advanced HBM** and Next Generation products are becoming more challenging in terms of pad pitch, signal integrity, and power.

For both applications
Technoprobe is leveraging
on **Vertical MEMS** solution
and on a unique PC
architecture.



Growth drivers & trajectories





Growth drivers & trajectories



FRONT END

Drive advancements in Logic Semiconductor Testing

Proliferate high-speed, high-voltage, radio frequency and silicon photonics

Enter the High Bandwidth Memory (HBM) segment

BACK END

Strengthen positioning in Final Testing

Growth drivers & trajectories



BACK END

Strengthen positioning in Final Testing

03 | Technology & Testing FusionLink





We have applied the disaggregation to test interface hardware

Main motherboard

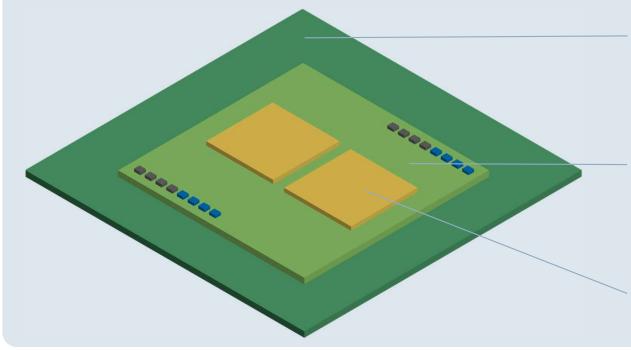
Best technology: printed circuit board (PCB)

Device substrate

Best technology: high density interconnect (HDI)

Probe substrate

Best technology: multi-layer organic (MLO)



Growth drivers & trajectories



FRONT END

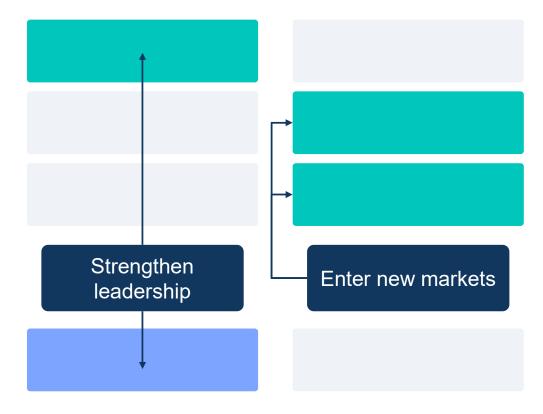
Advanced Packaging

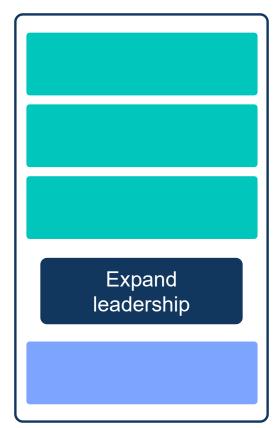
Radio frequency & silicon photonics

HBM

BACK END

FusionLink





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04 | **Financial Outlook**Stefano Beretta - CFO



Mid-terms scenario



1	Technological complexity evolution	 → Testing solution for Advanced Packaging → Increase in demand for high-precision tests
2	Market trends	 → Al will lead the growth for many market segments → Expansion of memory semiconductor segments
3	Geo-political instability	 → Technological sovereignty → Commercial policies

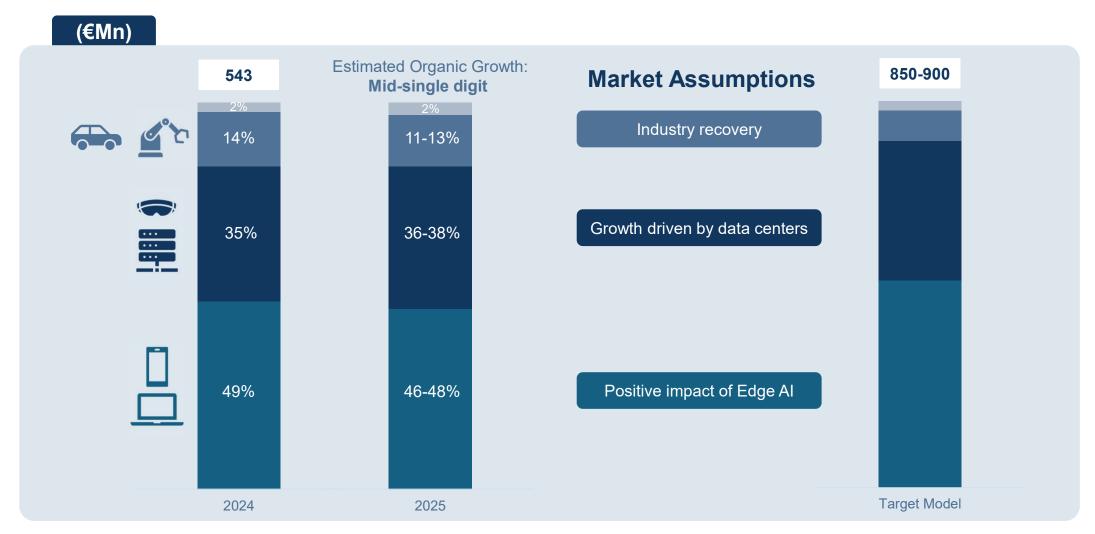
Market trends & revenues path





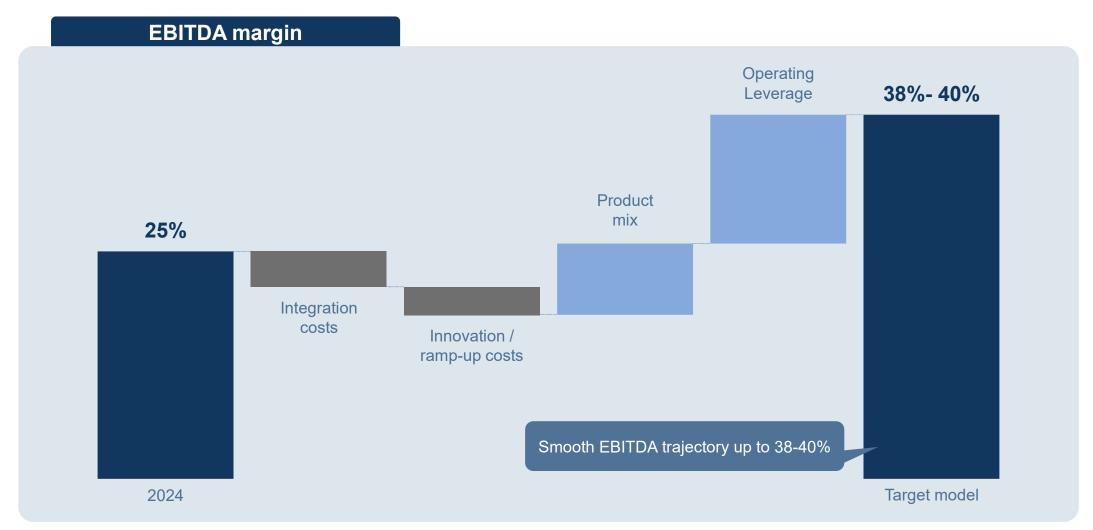
Market trends & revenues path





Profitability profile





Capex



(€Mn)







Capital Market Day 2025